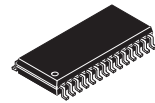




## MC9RS08LE4



28 W-SOIC  
Case 751F

## MC9RS08LE4

### Features:

- 8-Bit RS08 Central Processor Unit (CPU)
  - Up to 20 MHz CPU at 2.7 V to 5.5 V across temperature range of  $-40^{\circ}\text{C}$  to  $85^{\circ}\text{C}$
  - Subset of HC08 instruction set with added BGND instructions
- On-Chip Memory
  - 4 KB flash memory read/program/erase over full operating voltage and temperature
  - 256-byte random-access memory (RAM)
  - Security circuitry to prevent unauthorized access to flash memory contents
- Power-Saving Modes
  - Wait and stop
- Clock Source Options
  - Oscillator (XOSC) — Loop-control Pierce oscillator; crystal or ceramic resonator range of 31.25 kHz to 39.0625 kHz or 1 MHz to 20 MHz
  - Internal Clock Source (ICS) — Internal clock source module containing a frequency-locked-loop (FLL) controlled by internal or external reference; precision trimming of internal reference allows 0.2% resolution and 2% deviation over temperature and voltage; supports bus frequencies up to 10 MHz
- System Protection
  - Watchdog computer operating properly (COP) reset with option to run from dedicated 1 kHz internal clock source or bus clock
  - Low-voltage detection with reset or interrupt
  - Selectable trip points
  - Illegal opcode detection with reset
  - Illegal address detection with reset
  - Flash memory block protection
- Development Support
  - Single-wire background debug interface
- Breakpoint capability to allow single breakpoint setting during in-circuit debugging
- Peripherals
  - **LCD** — Up to  $8 \times 14$  or  $4 \times 18$  segments; compatible with 5 V or 3 V LCD glass displays using on-chip resistor bias network; functional in wait, stop modes for very low power LCD operation; frontplane and backplane pins multiplexed with GPIO functions; selectable frontplane and backplane configurations
  - **ADC** — 8-channel, 10-bit resolution; 2.5  $\mu\text{s}$  conversion time; automatic compare function; 1.7 mV/ $^{\circ}\text{C}$  temperature sensor; internal bandgap reference channel; operation in stop; fully functional from 2.7 V to 5.5 V.
  - **TPM** — Two 2-channel 16-bit timer/pulse-width modulator (TPM) modules; selectable input capture, output compare, or buffered edge- or center-aligned PWM on each channel
  - **SCI** — One serial communications interface module with optional 13-bit break; LIN extensions
  - **KBI** — 8-pin keyboard interrupt module
- Input/Output
  - 26 GPIOs including 1 output-only pin and 1 input-only pin
  - Hysteresis and configurable pullup device on all input pins; configurable slew rate and drive strength on all output pins
- Package Options
  - 28-pin SOIC

This document contains information on a product under development. Freescale reserves the right to change or discontinue this product without notice.

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## Revision History

To provide the most up-to-date information, the revision of our documents on the World Wide Web will be the most current. Your printed copy may be an earlier revision. To verify you have the latest information available, refer to:

<http://freescale.com/>

The following revision history table summarizes changes contained in this document.

Revision	Date	Description of Changes
1	10/6/2008	Initial public release.
2	11/3/2008	In <a href="#">Table 8</a> , updated the WIDD, added the maximum of RIDD and SIDD at 5 V and deleted RTI adder from stop with 32.768 kHz crystal external clock source reference enabled. Added maximum of $I_{OLT}$ in <a href="#">Table 7</a> .
3	12/4/2009	Updated the part number information.

## Related Documentation

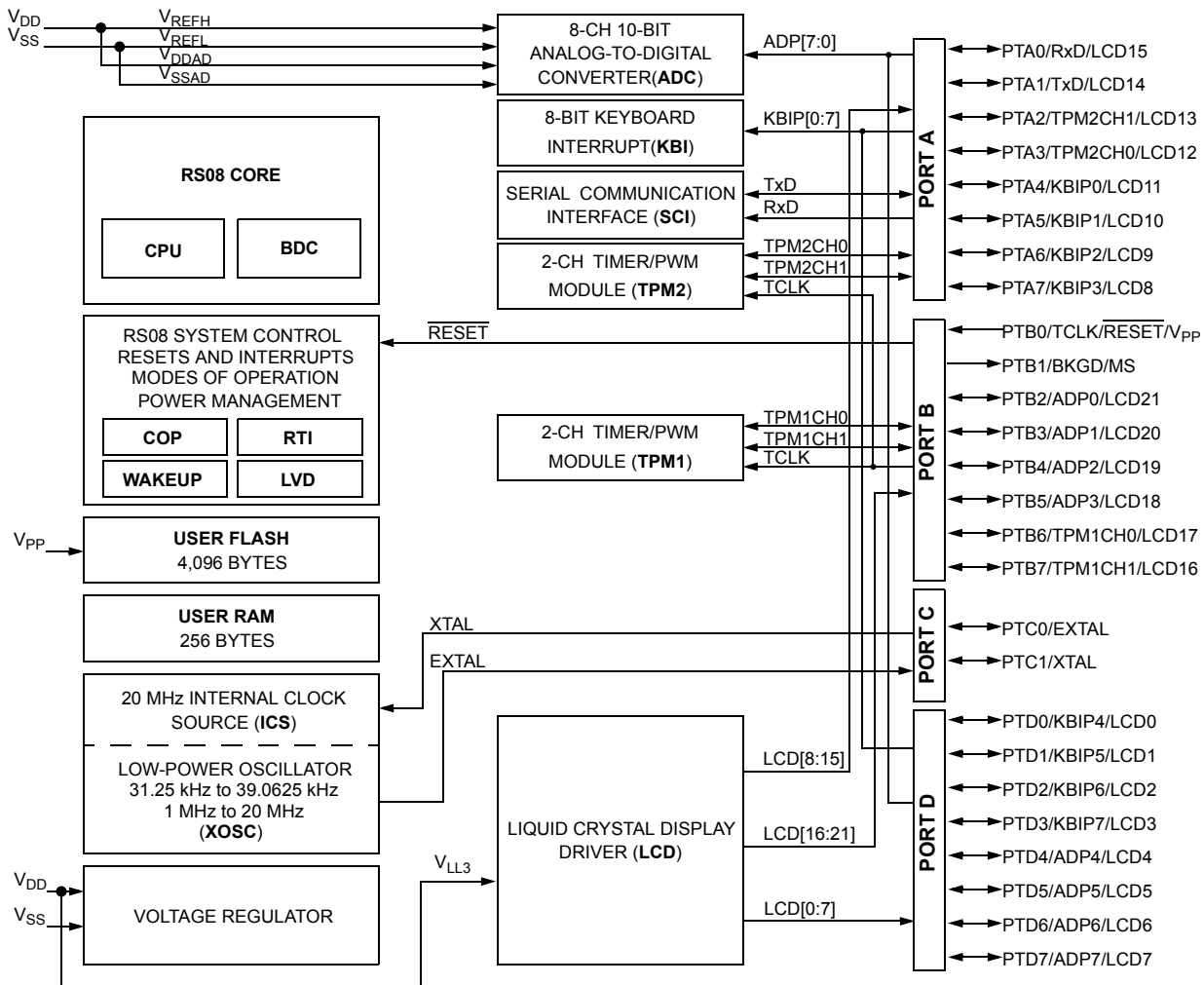
Find the most current versions of all documents at: <http://www.freescale.com>

### Reference Manual (MC9RS08LE4RM)

Contains extensive product information including modes of operation, memory, resets and interrupts, register definition, port pins, CPU, and all module information.

# 1 MCU Block Diagram

The block diagram, [Figure 1](#), shows the structure of the MC9RS08LE4 MCU.



**NOTES:**

1. PTB0/TCLK/RESET/V<sub>PP</sub> is an input-only pin when used as port pin
2. PTB1/BKGD/MS is an output-only pin

**Figure 1. MC9RS08LE4 Block Diagram**

# 2 Pin Assignments

This section shows the pin assignments in the packages available for the MC9RS08LE4.

**Table 2-1. Pin Availability by Package Pin-Count**

Pin Number	<-- Lowest Priority --> Highest			
	Port Pin	Alt 1	Alt 2	Alt 3
1	PTD3		KBIP7	LCD3
2	PTD2		KBIP6	LCD2
3	PTD1		KBIP5	LCD1
4	PTD0		KBIP4	LCD0
5				V <sub>DD</sub>
6				V <sub>SS</sub>
7	PTC0		EXTAL	
8	PTC1		XTAL	
9	PTB0	TCLK	<u>RESET</u>	V <sub>PP</sub>
10	PTB1		BKGD	MS
11	PTB2		ADP0	LCD21
12	PTB3		ADP1	LCD20
13	PTB4		ADP2	LCD19
14	PTB5		ADP3	LCD18
15	PTB6		TPM1CH0	LCD17
16	PTB7		TPM1CH1	LCD16
17	PTA0		RxD	LCD15
18	PTA1		TxD	LCD14
19	PTA2		TPM2CH1	LCD13
20	PTA3		TPM2CH0	LCD12
21	PTA4		KBIP0	LCD11
22	PTA5		KBIP1	LCD10
23	PTA6		KBIP2	LCD9
24	PTA7		KBIP3	LCD8
25	PTD7		ADP7	LCD7
26	PTD6		ADP6	LCD6
27	PTD5		ADP5	LCD5
28	PTD4		ADP4	LCD4

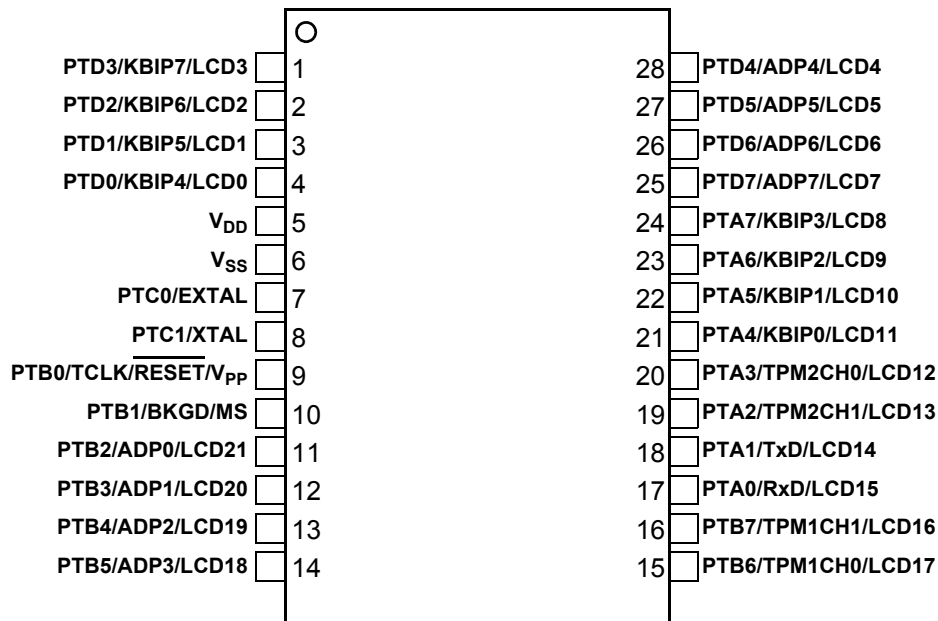


Figure 2. MC9RS08LE4 in 28-Pin SOIC Package

## 3 Electrical Characteristics

### 3.1 Introduction

This section contains electrical and timing specifications for the MC9RS08LE4 microcontroller available at the time of publication.

### 3.2 Parameter Classification

The electrical parameters shown in this supplement are guaranteed by various methods. To give the customer a better understanding the following classification is used and the parameters are tagged accordingly in the tables where appropriate:

Table 2. Parameter Classifications

<b>P</b>	Those parameters are guaranteed during production testing on each individual device.
<b>C</b>	Those parameters are achieved by the design characterization by measuring a statistically relevant sample size across process variations.
<b>T</b>	Those parameters are achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted. All values shown in the typical column are within this category.
<b>D</b>	Those parameters are derived mainly from simulations.

**NOTE**

The classification is shown in the column labeled “C” in the parameter tables where appropriate.

### 3.3 Absolute Maximum Ratings

Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stress beyond the limits specified in Table 3 may affect device reliability or cause permanent damage to the device. For functional operating conditions, refer to the remaining tables in this chapter.

This device contains circuitry protecting against damage due to high static voltage or electrical fields; however, it is advised that normal precautions be taken to avoid application of any voltages higher than maximum-rated voltages to this high-impedance circuit. Reliability of operation is enhanced if unused inputs are tied to an appropriate logic voltage level (for instance, either  $V_{SS}$  or  $V_{DD}$ ) or the programmable pull-up resistor associated with the pin is enabled.

**Table 3. Absolute Maximum Ratings**

Rating	Symbol	Value	Unit
Supply voltage	$V_{DD}$	2.7 to 5.5	V
Maximum current into $V_{DD}$	$I_{DD}$	120	mA
Digital input voltage	$V_{In}$	-0.3 to $V_{DD} + 0.3$	V
Instantaneous maximum current Single pin limit (applies to all port pins) <sup>1, 2, 3</sup>	$I_D$	±25	mA
Storage temperature range	$T_{stg}$	-55 to 150	°C

<sup>1</sup> Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive ( $V_{DD}$ ) and negative ( $V_{SS}$ ) clamp voltages, then use the larger of the two resistance values.

<sup>2</sup> All functional non-supply pins are internally clamped to  $V_{SS}$  and  $V_{DD}$  except the  $\overline{RESET}/V_{PP}$  pin which is internally clamped to  $V_{SS}$  only.

<sup>3</sup> Power supply must maintain regulation within operating  $V_{DD}$  range during instantaneous and operating maximum current conditions. If positive injection current ( $V_{In} > V_{DD}$ ) is greater than  $I_{DD}$ , the injection current may flow out of  $V_{DD}$  and could result in external power supply going out of regulation. Ensure external  $V_{DD}$  load will shunt current greater than maximum injection current. This will be the greatest risk when the MCU is not consuming power. Examples are: if no system clock is present, or if the clock rate is very low which would reduce overall power consumption.

### 3.4 Thermal Characteristics

This section provides information about operating temperature range, power dissipation, and package thermal resistance. Power dissipation on I/O pins is usually small compared to the power dissipation in on-chip logic and voltage regulator circuits and it is user-determined rather than being controlled by the MCU design. In order to take PI/O into account in power calculations, determine the difference between actual pin voltage and  $V_{SS}$  or  $V_{DD}$  and multiply by the pin current for each I/O pin. Except in cases of unusually high pin current (heavy loads), the difference between pin voltage and  $V_{SS}$  or  $V_{DD}$  will be very small.

**Table 4. Thermal Characteristics**

Rating	Symbol	Value	Unit
Operating temperature range (packaged)	$T_A$	$T_L$ to $T_H$ -40 to 85	°C
Maximum junction temperature	$T_{JMAX}$	105	°C
Thermal resistance Single layer board 28-pin SOIC	$\theta_{JA}$	70	°C/W

The average chip-junction temperature ( $T_J$ ) in °C can be obtained from:

$$T_J = T_A + (P_D \times \theta_{JA}) \tag{Eqn. 1}$$

where:

$T_A$  = Ambient temperature, °C

$\theta_{JA}$  = Package thermal resistance, junction-to-ambient, °C /W

$P_D = P_{int} + P_{I/O}$

$P_{int} = I_{DD} \times V_{DD}$ , Watts chip internal power

$P_{I/O}$  = Power dissipation on input and output pins user determined

For most applications,  $P_{I/O} \ll P_{int}$  and can be neglected. An approximate relationship between  $P_D$  and  $T_J$  (if  $P_{I/O}$  is neglected) is:

$$P_D = K \div (T_J + 273^\circ\text{C}) \tag{Eqn. 2}$$

Solving Equation 1 and Equation 2 for K gives:

$$K = P_D \times (T_A + 273^\circ\text{C}) + \theta_{JA} \times (P_D)^2 \tag{Eqn. 3}$$

where K is a constant pertaining to the particular part. K can be determined from Equation 3 by measuring  $P_D$  (at equilibrium) for a known  $T_A$ . Using this value of K, the values of  $P_D$  and  $T_J$  can be obtained by solving equations 1 and 2 iteratively for any value of  $T_A$ .

### 3.5 ESD Protection and Latch-Up Immunity

Although damage from electrostatic discharge (ESD) is much less common on these devices than on early CMOS circuits, normal handling precautions must be used to avoid exposure to static discharge. Qualification tests are performed to ensure that these devices can withstand exposure to reasonable levels of static without suffering any permanent damage.

All ESD testing is in conformity with AEC-Q100 Stress Test Qualification for Automotive Grade Integrated Circuits. During the device qualification ESD stresses were performed for the human body model (HBM), the machine model (MM) and the charge device model (CDM).

A device is defined as a failure if after exposure to ESD pulses the device no longer meets the device specification. Complete DC parametric and functional testing is performed per the applicable device

## DC Characteristics

specification at room temperature followed by hot temperature, unless specified otherwise in the device specification.

**Table 5. ESD and Latch-up Test Conditions**

Model	Description	Symbol	Value	Unit
Human Body	Series resistance	R1	1500	$\Omega$
	Storage capacitance	C	100	pF
	Number of pulses per pin	—	3	—
Machine	Series resistance	R1	0	$\Omega$
	Storage capacitance	C	200	pF
	Number of pulses per pin	—	3	—
Latch-up	Minimum input voltage limit	—	-2.5	V
	Maximum input voltage limit	—	7.5	V

**Table 6. ESD and Latch-Up Protection Characteristics**

No.	Rating <sup>1</sup>	Symbol	Min	Max	Unit
1	Human body model (HBM)	$V_{HBM}$	$\pm 2000$	—	V
2	Machine model (MM)	$V_{MM}$	$\pm 200$	—	V
3	Charge device model (CDM)	$V_{CDM}$	$\pm 500$	—	V
4	Latch-up current at $T_A = 85^\circ\text{C}$	$I_{LAT}$	$\pm 100^2$	—	mA
	Latch-up current at $T_A = 85^\circ\text{C}$	$I_{LAT}$	$\pm 75^3$	—	mA

<sup>1</sup> Parameter is achieved by design characterization on a small sample size from typical devices under typical conditions unless otherwise noted.

<sup>2</sup> These pins meet JESD78A Class II (section 1.2) Level A (section 1.3) requirement of  $\pm 100$  mA.

<sup>3</sup> This pin meets JESD78A Class II (section 1.2) Level B (section 1.3) characterization to  $\pm 75$  mA.

## 3.6 DC Characteristics

This section includes information about power supply requirements, I/O pin characteristics, and power supply current in various operating modes.

**Table 7. DC Characteristics (Temperature Range =  $-40$  to  $85^\circ\text{C}$  Ambient)**

Num	C	Parameter	Symbol	Min	Typical	Max	Unit
1		Supply voltage (run, wait and stop modes.) $0 < f_{Bus} < 10\text{MHz}$	$V_{DD}$	2.7	—	5.5	—
2	C	Minimum RAM retention supply voltage applied to $V_{DD}$	$V_{RAM}$	$0.8^1$	—	—	V
3	P	Low-voltage Detection threshold ( $V_{DD}$ falling) ( $V_{DD}$ rising)	$V_{LVD}$	1.80 1.88	1.86 1.94	1.95 2.03	V
4	C	Power on RESET (POR) voltage	$V_{POR}$	0.9	—	1.7	V
5	C	Input high voltage ( $V_{DD} > 2.3\text{V}$ ) (all digital inputs)	$V_{IH}$	$0.70 \times V_{DD}$	—	—	V
		Input high voltage ( $1.8\text{V} \leq V_{DD} \leq 2.3\text{V}$ ) (all digital inputs)		$0.85 \times V_{DD}$	—	—	V



**Table 7. DC Characteristics (Temperature Range = –40 to 85°C Ambient) (continued)**

Num	C	Parameter	Symbol	Min	Typical	Max	Unit
6	C	Input low voltage ( $V_{DD} > 2.3$ V) (all digital inputs)	$V_{IL}$	—	—	$0.30 \times V_{DD}$	V
		Input low voltage ( $1.8 \text{ V} \leq V_{DD} \leq 2.3$ V) (all digital inputs)		—	—	$0.30 \times V_{DD}$	V
7	C	Input hysteresis (all digital inputs)	$V_{hys}$	$0.06 \times V_{DD}$	—	—	V
8	P	Input leakage current (per pin) $V_{In} = V_{DD}$ or $V_{SS}$ , all input only pins	$ I_{In} $	—	0.025	1.0	$\mu\text{A}$
9	P	High impedance (off-state) leakage current (per pin) $V_{In} = V_{DD}$ or $V_{SS}$ , all input/output	$ I_{OZ} $	—	0.025	1.0	$\mu\text{A}$
10	P	Internal pullup/pulldown resistors <sup>2</sup> (all port pins)	$R_{PU}$	20	45	65	$\text{k}\Omega$
11	C	Output high voltage (port A) $I_{OH} = -5$ mA ( $V_{DD} \geq 4.5$ V)	$V_{OH}$	$V_{DD} - 0.8$	—	—	V
		$I_{OH} = -3$ mA ( $V_{DD} \geq 3$ V)			—	—	
		$I_{OH} = -2$ mA ( $V_{DD} \geq 1.8$ V)			—	—	
12	C	Maximum total $I_{OH}$ for all port pins	$ I_{OHT} $	—	—	40	mA
13	C	Output low voltage (port A) $I_{OL} = 5$ mA ( $V_{DD} \geq 4.5$ V)	$V_{OL}$	—	—	0.8	V
		$I_{OL} = 3$ mA ( $V_{DD} \geq 3$ V)		—	—	0.8	
		$I_{OL} = 2$ mA ( $V_{DD} \geq 1.8$ V)		—	—	0.8	
14	C	Maximum total $I_{OL}$ for all port pins	$I_{OLT}$	—	—	100	mA
15	C	dc injection current <sup>3, 4, 5, 6</sup> $V_{In} < V_{SS}$ , $V_{In} > V_{DD}$ Single pin limit	—	—	—	0.2	mA
		Total MCU limit, includes sum of all stressed pins	—	—	—	0.8	mA
16	C	Input capacitance (all non-supply pins)	$C_{In}$	—	—	7	pF

<sup>1</sup> This parameter is characterized and not tested on each device.

<sup>2</sup> Measurement condition for pull resistors:  $V_{In} = V_{SS}$  for pullup and  $V_{In} = V_{DD}$  for pulldown.

<sup>3</sup> All functional non-supply pins are internally clamped to  $V_{SS}$  and  $V_{DD}$  except the  $\overline{\text{RESET}}/V_{PP}$  which is internally clamped to  $V_{SS}$  only

<sup>4</sup> Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.

<sup>5</sup> Input must be current limited to the value specified. To determine the value of the required current-limiting resistor, calculate resistance values for positive and negative clamp voltages, then use the larger of the two values.

<sup>6</sup> This parameter is characterized and not tested on each device.

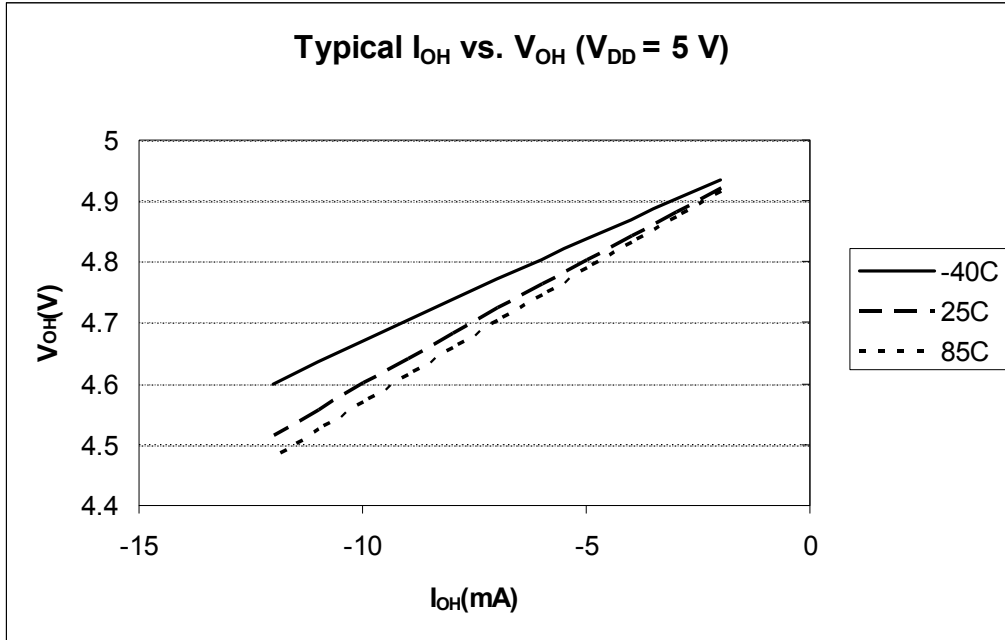


Figure 3. Typical  $I_{OH}$  vs.  $V_{OH}$  ( $V_{DD} = 5\text{ V}$ )

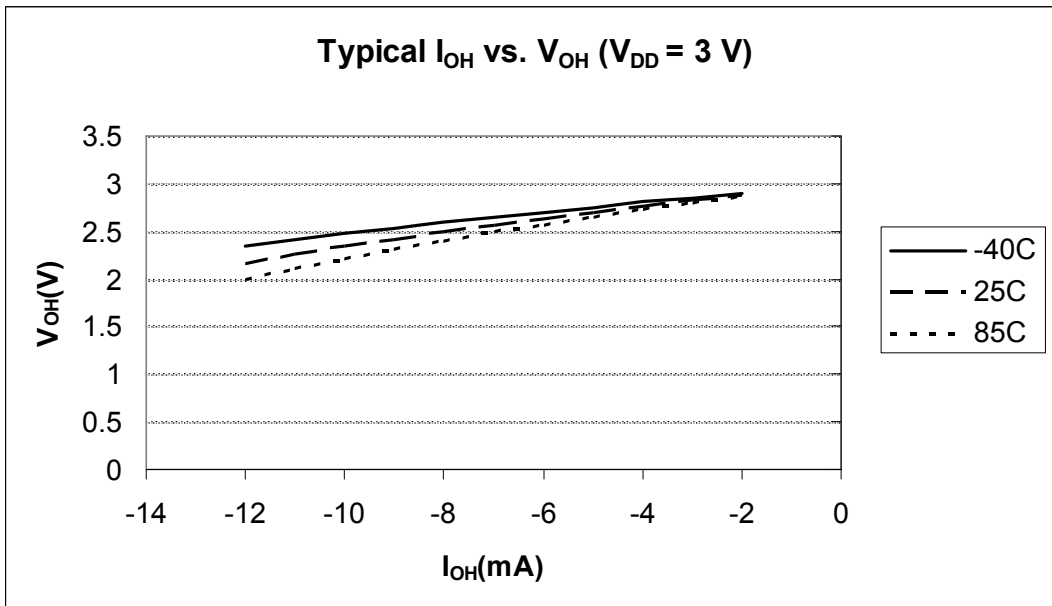


Figure 4. Typical  $I_{OH}$  vs.  $V_{OH}$  ( $V_{DD} = 3\text{ V}$ )

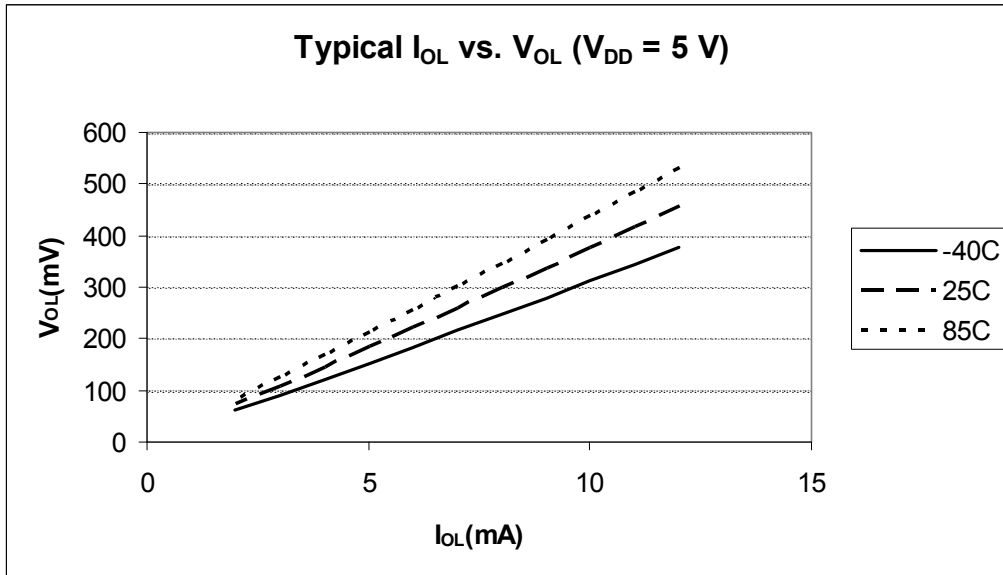


Figure 5. Typical  $I_{OL}$  vs.  $V_{OL}$  ( $V_{DD} = 5\text{ V}$ )

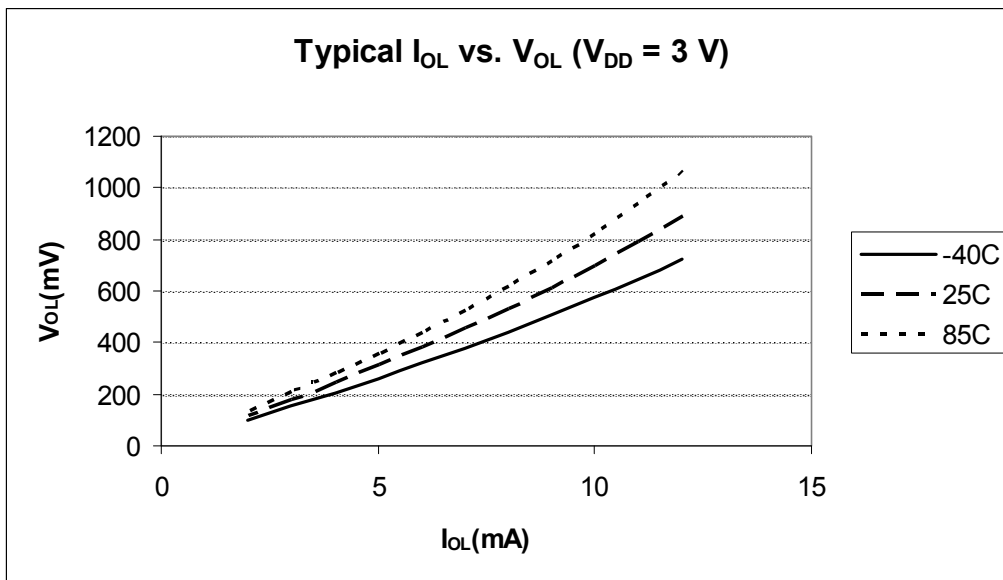


Figure 6. Typical  $I_{OL}$  vs.  $V_{OL}$  ( $V_{DD} = 3\text{ V}$ )

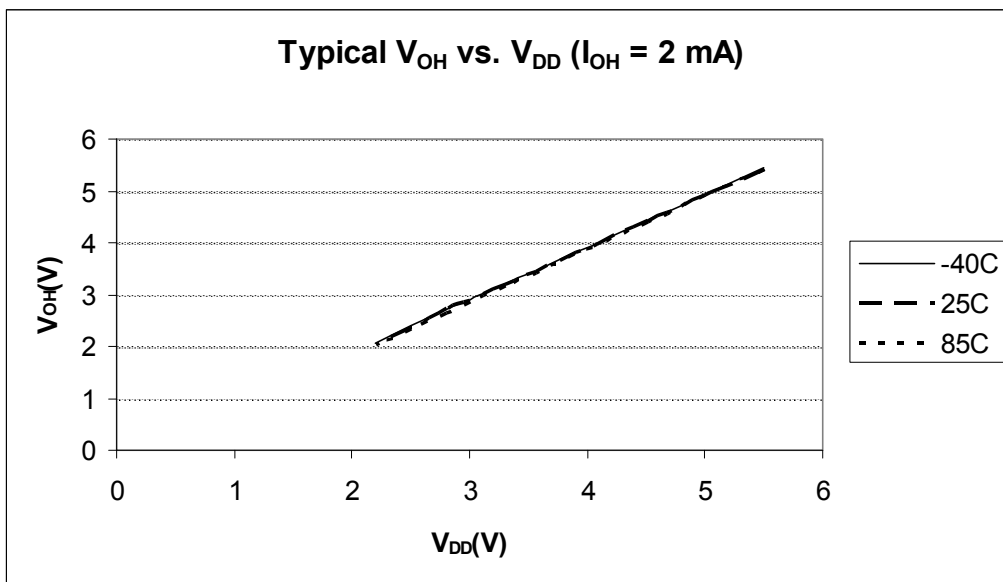


Figure 7. Typical  $V_{OH}$  vs.  $V_{DD}$  ( $I_{OH} = 2 \text{ mA}$ )

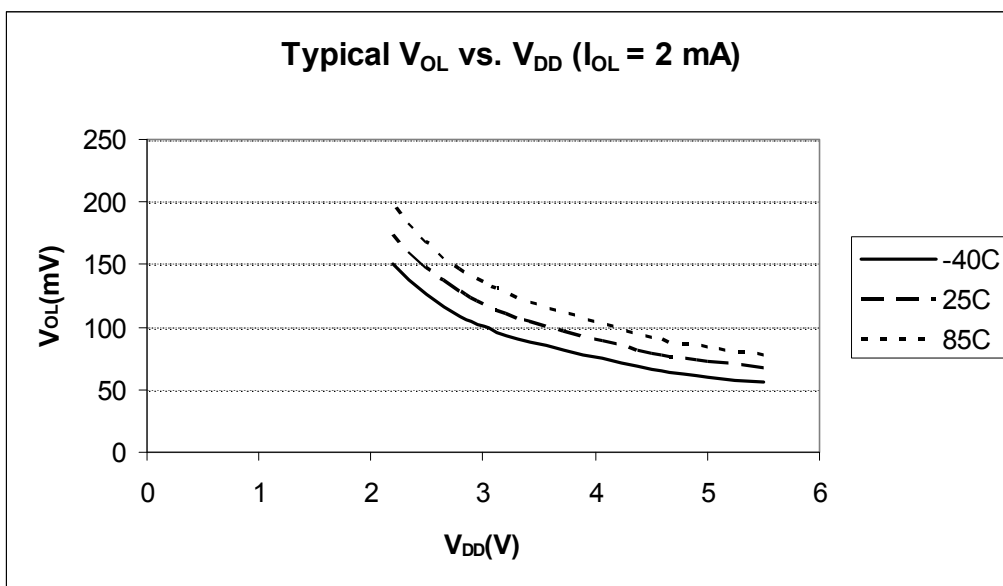


Figure 8. Typical  $V_{OL}$  vs.  $V_{DD}$  ( $I_{OL} = 2 \text{ mA}$ )

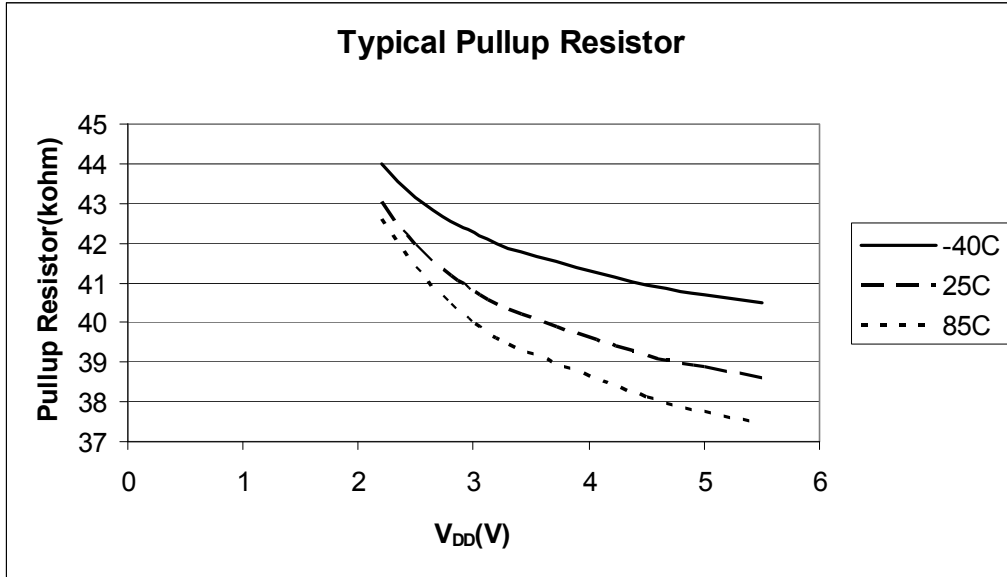


Figure 9. Typical Pullup Resistor

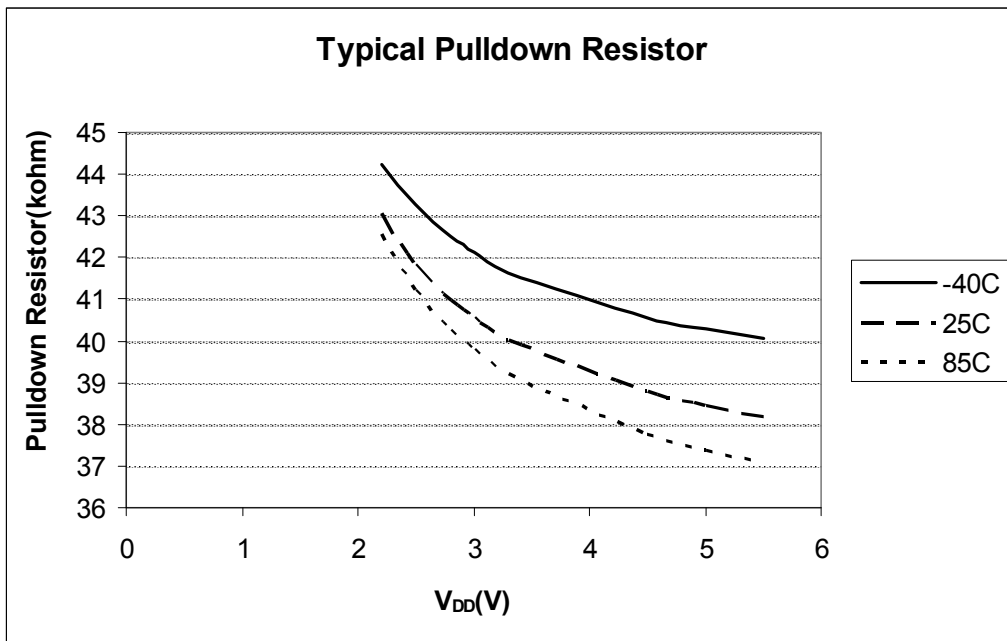


Figure 10. Typical Pulldown Resistor

### 3.7 Supply Current Characteristics

Table 8. Supply Current Characteristics

Num	C	Parameter	Symbol	Bus Freq. (MHz)	V <sub>DD</sub> (V)	Temp. (°C)	Typical	Max <sup>1</sup>	Unit
1	P	Run supply current <sup>2</sup>	RIDD	10	5	-40	3.78	20	mA
	25					3.81			
	85			3.83					
	C			3	-40	3.70	—		
25	3.76								
85	3.77								
2	T	Wait supply current <sup>2</sup>	WIDD	2	5	-40	932	—	μA
	25					943			
	85			947					
	T			3	-40	940	—		
25	959								
85	954								
3	T	ADC adder to stop <sup>3</sup>	—	1	5	-40	712	—	μA
	25					714			
	85			717					
	T			3	-40	718	—		
25	716								
85	715								
3	P	Stop mode supply current	SIDD	—	5	-40	1.14	15	μA
	25					1.43			
C	3	-40	0.61	—					
25		0.88							
85	2.96								
4	T	RTI adder from stop with 1 kHz clock source enabled	—	—	5	-40	0.10	—	μA
	25					0.11			
85	0.12								
5	T	—	—	—	3	-40	0.11	—	μA
	25					0.11			
85	0.12								

Table 8. Supply Current Characteristics (continued)

Num	C	Parameter	Symbol	Bus Freq. (MHz)	V <sub>DD</sub> (V)	Temp. (°C)	Typical	Max <sup>1</sup>	Unit
6	T	LVI adder from stop (LVDE = 1 and LVDSE = 1)	—	—	5	-40	69.40	—	μA
						25	72.07	—	
						85	73.29	—	
	T			—	3	-40	69.74	—	
						25	72.19	—	
						85	72.67	—	

<sup>1</sup> Maximum value is measured at the nominal V<sub>DD</sub> voltage times 10% tolerance. Values given here are preliminary estimates prior to completing characterization

<sup>2</sup> Does not include any dc loads on port pins

<sup>3</sup> Required asynchronous ADC clock and LVD to be enabled.

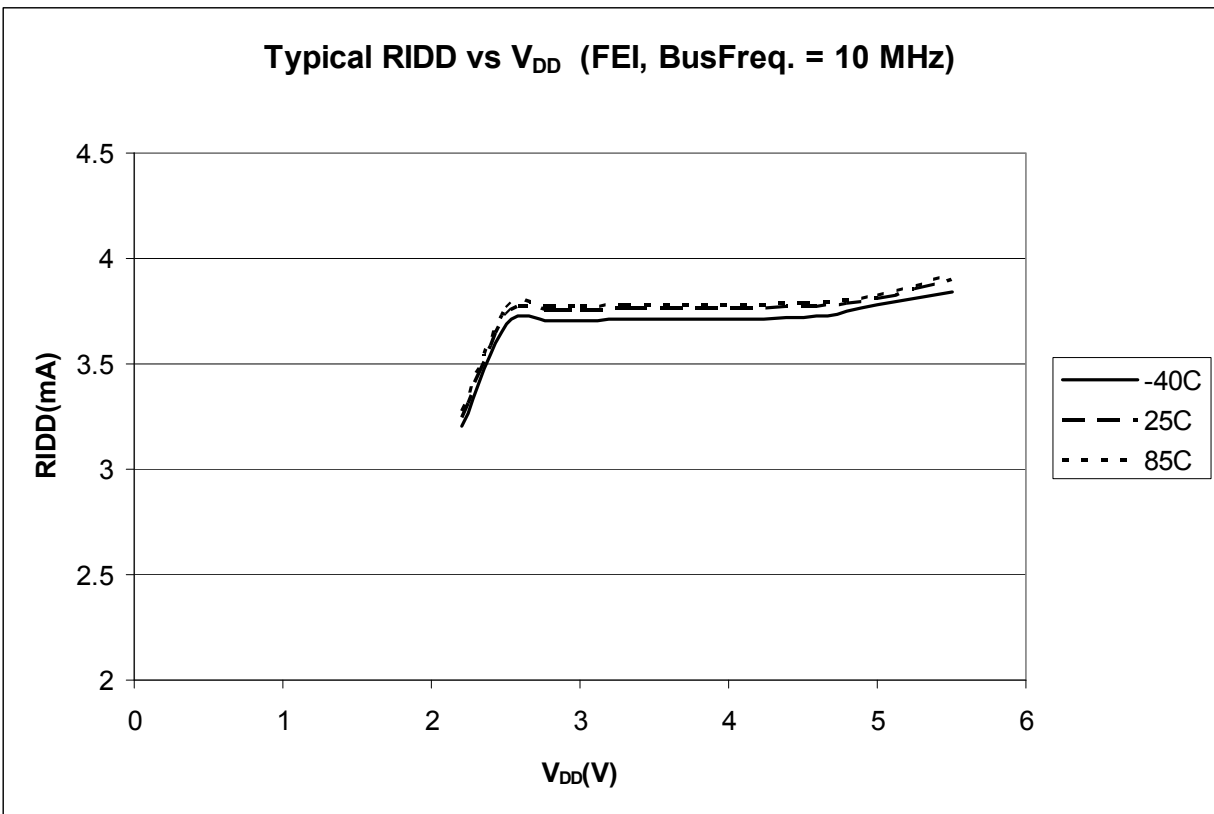


Figure 11. Typical RIDD vs. V<sub>DD</sub> (FEI, BusFreq. = 10 MHz)

### 3.8 External Oscillator (XOSC) Characteristics

Refer to [Figure 12](#) for crystal or resonator circuit.

**Table 9. External Oscillator Specifications (Temperature Range = -40 to 85°C Ambient)**

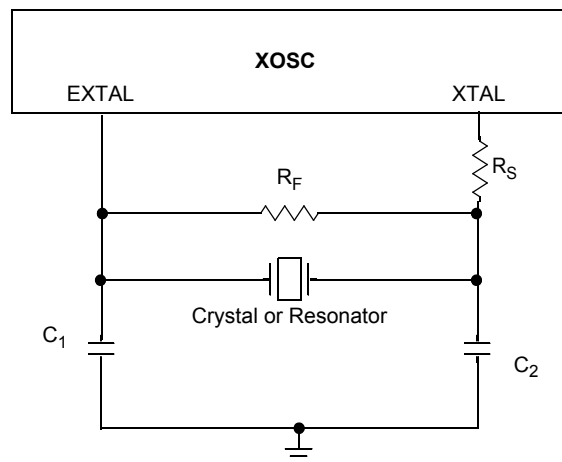
Num	C	Characteristic	Symbol	Min	Typical <sup>1</sup>	Max	Unit
1	D	Oscillator crystal or resonator (EREFS = 1) Low range, ( IREFS = x)	$f_{lo}$	32	—	38.4	kHz
		High range, FLL bypassed external (CLKS = 10, IREFS = x)	$f_{hi\_byp}$	1	—	5	MHz
		High range, FLL engaged external (CLKS = 00, IREFS = 0)	$f_{hi\_eng}$	1	—	5	MHz
2	D	Load capacitors	$C_1$ $C_2$	See Note <sup>2</sup>			
3	D	Feedback resistor Low range (32 kHz to 100 kHz) High range (1 MHz to 16 MHz)	$R_F$		10 1		MΩ
4	D	Series resistor Low range Low Gain (HGO = 0)	$R_S$	—	0	—	kΩ
		High Gain (HGO = 1)		—	100	—	
		High range Low Gain (HGO = 0)		—	0	—	
		High Gain (HGO = 1) ≥ 8 MHz		—	0	—	
		4 MHz		—	10	—	
1 MHz	—	20	—				
5	D	Crystal start-up time <sup>3,4</sup> Low range High range	$t_{CSTL}$ $t_{CSTH}$	— —	500 4	— —	ms

<sup>1</sup> Data in Typical column was characterized at 3.0 V, 25 °C or is typical recommended value.

<sup>2</sup> See crystal or resonator manufacturer’s recommendation.

<sup>3</sup> This parameter is characterized and not tested on each device.

<sup>4</sup> Proper PC board layout procedures must be followed to achieve specifications.



**Figure 12. Typical Crystal or Resonator Circuit**



## 3.9 Internal Clock Source (ICS) Characteristics

**Table 10. ICS Frequency Specifications (Temperature Range = –40 to 85°C Ambient)**

Num	C	Characteristic	Symbol	Min	Typical <sup>1</sup>	Max	Unit
1	C	Square wave input clock frequency (EREFS = 0) FLL bypass external (CLKS = 10) FLL engaged external (CLKS = 00)	$f_{\text{extal}}$	0 0.03125	— —	20 5	MHz
2	C	Average internal reference frequency - untrimmed	$f_{\text{int\_ut}}$	25	31.25	41.66	kHz
3	C	Average internal reference frequency - trimmed	$f_{\text{int\_t}}$	31.25	31.25	39.0625	kHz
4	C	DCO output frequency range — untrimmed	$f_{\text{dco\_ut}}$	12.8	16	21.33	MHz
5	C	DCO output frequency range — trimmed	$f_{\text{dco\_t}}$	16	16	20	MHz
6	C	Resolution of trimmed DCO output frequency at fixed voltage and temperature	$\Delta f_{\text{dco\_res\_t}}$	—	—	±0.2	% $f_{\text{dco}}$
7	C	Total deviation of trimmed DCO output frequency over voltage and temperature	$\Delta f_{\text{dco\_t}}$	—	—	±2	% $f_{\text{dco}}$
8	C	FLL acquisition time <sup>3,2</sup>	$t_{\text{acquire}}$	—	—	1	ms
9	C	Long term Jitter <sup>3</sup> of DCO output clock (averaged over 2 ms interval)	$C_{\text{Jitter}}$	—	—	0.6	% $f_{\text{dco}}$

<sup>1</sup> Data in Typical column was characterized at 3.0 V, 25 °C or is typical recommended value.

<sup>2</sup> This specification applies to any time the FLL reference source or reference divider is changed, trim value changed or changing from FLL disabled (FBELP, FBILP) to FLL enabled (FEI, FEE, FBE, FBI). If a crystal/resonator is being used as the reference, this specification assumes it is already running.

<sup>3</sup> Jitter is the average deviation from the programmed frequency measured over the specified interval at maximum  $f_{\text{BUS}}$ . Measurements are made with the device powered by filtered supplies and clocked by a stable external clock signal. Noise injected into the FLL circuitry via  $V_{\text{DD}}$  and  $V_{\text{SS}}$  and variation in crystal oscillator frequency increase the  $C_{\text{Jitter}}$  percentage for a given interval.

## 3.10 AC Characteristics

This section describes AC timing characteristics for each peripheral system.

### 3.10.1 Control Timing

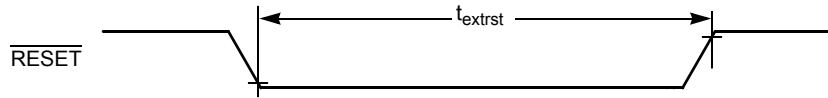
**Table 11. Control Timing**

Num	C	Parameter	Symbol	Min	Typical	Max	Unit
1	D	Bus frequency ( $t_{\text{cyc}} = 1/f_{\text{Bus}}$ )	$f_{\text{Bus}}$	0	—	10	MHz
2	D	Real time interrupt internal oscillator period	$t_{\text{RTI}}$	700	1000	1300	μs
3	D	External $\overline{\text{RESET}}$ pulse width <sup>1</sup>	$t_{\text{extrst}}$	150	—	—	ns
4	D	KBI pulse width <sup>2</sup>	$t_{\text{KBIPW}}$	$1.5 t_{\text{cyc}}$	—	—	ns
5	D	KBI pulse width in stop <sup>1</sup>	$t_{\text{KBIPWS}}$	100	—	—	ns
6	C	Port rise and fall time (load = 50 pF) <sup>3</sup> Slew rate control disabled (PTxSE = 0) Slew rate control enabled (PTxSE = 1)	$t_{\text{Rise}}, t_{\text{Fall}}$	— —	11 35	— —	ns

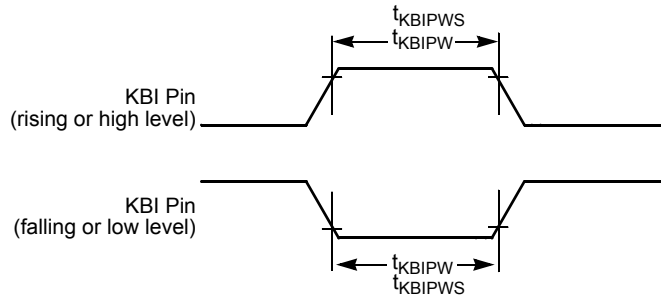
<sup>1</sup> This is the shortest pulse that is guaranteed to pass through the pin input filter circuitry. Shorter pulses may or may not be recognized.

### AC Characteristics

- 2 This is the minimum pulse width that is guaranteed to pass through the pin synchronization circuitry. Shorter pulses may or may not be recognized. In stop mode, the synchronizer is bypassed so shorter pulses can be recognized in that case.
- 3 Timing is shown with respect to 20%  $V_{DD}$  and 80%  $V_{DD}$  levels. Temperature range  $-40\text{ }^{\circ}\text{C}$  to  $85\text{ }^{\circ}\text{C}$ .



**Figure 13. Reset Timing**



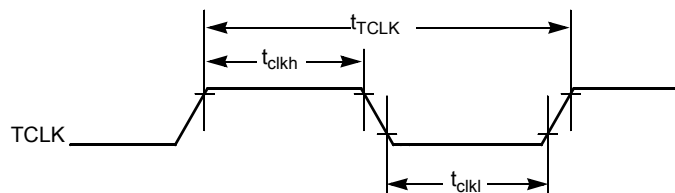
**Figure 14. KBI Pulse Width**

### 3.10.2 TPM Module Timing

Synchronizer circuits determine the shortest input pulses that can be recognized or the fastest clock that can be used as the optional external source to the timer counter. These synchronizers operate from the current bus rate clock.

**Table 12. TPM/MTIM Input Timing**

Num	C	Function	Symbol	Min	Max	Unit
1	D	External clock frequency	$f_{TCLK}$	0	$f_{Bus}/4$	MHz
2	D	External clock period	$t_{TCLK}$	4	—	$t_{CYC}$
3	D	External clock high time	$t_{clkh}$	1.5	—	$t_{CYC}$
4	D	External clock low time	$t_{clkl}$	1.5	—	$t_{CYC}$
5	D	Input capture pulse width	$f_{ICPW}$	1.5	—	$t_{CYC}$



**Figure 15. Timer External Clock**

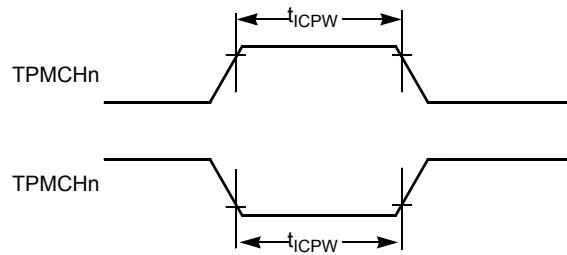


Figure 16. Timer Input Capture Pulse

### 3.11 ADC Characteristics

Figure 17. 5 Volt 10-bit ADC Operating Conditions

Characteristic	Conditions	Symb	Min	Typical <sup>1</sup>	Max	Unit
Supply voltage	Absolute	$V_{DDAD}$	1.8	—	5.5	V
	Delta to $V_{DD}$ ( $V_{DD} - V_{DDAD}$ ) <sup>2</sup>	$\Delta V_{DDAD}$	-100	0	100	mV
Ground voltage	Delta to $V_{SS}$ ( $V_{SS} - V_{SSAD}$ ) <sup>2</sup>	$\Delta V_{SSAD}$	-100	0	100	mV
Reference voltage high		$V_{REFH}$	1.8	$V_{DDAD}$	$V_{DDAD}$	V
Reference voltage low		$V_{REFL}$	$V_{SSAD}$	$V_{SSAD}$	$V_{SSAD}$	V
Input voltage		$V_{ADIN}$	$V_{REFL}$	—	$V_{REFH}$	V
Input capacitance		$C_{ADIN}$	—	4.5	5.5	pF
Input resistance		$R_{ADIN}$	—	3	5	k $\Omega$
Analog source resistance external to MCU	10 bit mode $f_{ADCK} > 4\text{MHz}$ $f_{ADCK} < 4\text{MHz}$	$R_{AS}$	—	—	5	k $\Omega$
	8 bit mode (all valid $f_{ADCK}$ )		—	—	10	
ADC conversion clock frequency	High speed (ADLPC = 0)	$f_{ADCK}$	0.4	—	8.0	MHz
	Low power (ADLPC = 1)		0.4	—	4.0	

<sup>1</sup> Typical values assume  $V_{DDAD} = 5.0\text{ V}$ , Temp = 25 °C,  $f_{ADCK} = 1.0\text{ MHz}$  unless otherwise stated. Typical values are for reference only and are not tested in production.

<sup>2</sup> DC potential difference.

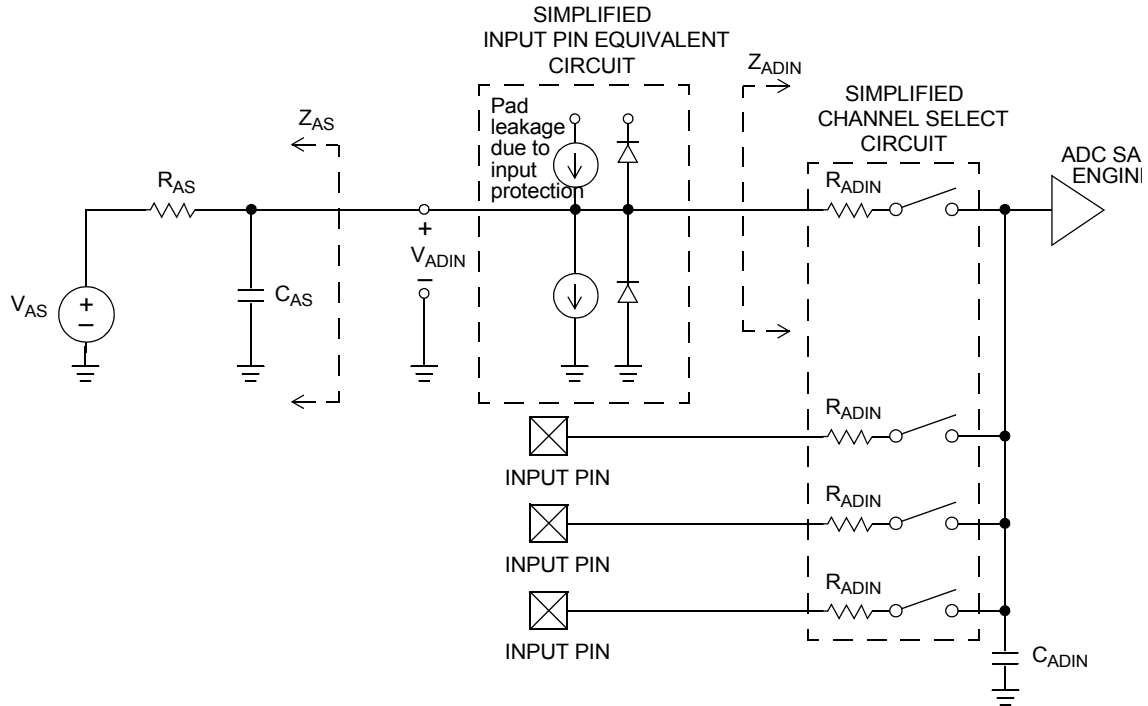


Figure 18. ADC Input Impedance Equivalency Diagram

Table 13. 10-bit ADC Characteristics ( $V_{REFH} = V_{DDAD}$ ,  $V_{REFL} = V_{SSAD}$ )

Num	C	Characteristic	Conditions	Symb	Min	Typical <sup>1</sup>	Max	Unit
1	T	Supply current ADLPC=1 ADLSMP=1 ADCO=1		$I_{DDAD}$	—	133	—	$\mu\text{A}$
2	T	Supply current ADLPC=1 ADLSMP=0 ADCO=1		$I_{DDAD}$	—	218	—	$\mu\text{A}$
3	T	Supply current ADLPC=0 ADLSMP=1 ADCO=1		$I_{DDAD}$	—	327	—	$\mu\text{A}$
4	P	Supply current ADLPC=0 ADLSMP=0 ADCO=1	$V_{DDAD} \leq 5.5 \text{ V}$	$I_{DDAD}$	—	0.582	1	mA
5		Supply current	Stop, reset, module off	$I_{DDAD}$	—	0.011	1	$\mu\text{A}$
6	P	ADC asynchronous clock source	High speed (ADLPC = 0)	$f_{ADACK}$	2	3.3	5	MHz
			Low power (ADLPC = 1)		1.25	2	3.3	

**Table 13. 10-bit ADC Characteristics ( $V_{REFH} = V_{DDAD}$ ,  $V_{REFL} = V_{SSAD}$ ) (continued)**

Num	C	Characteristic	Conditions	Symb	Min	Typical <sup>1</sup>	Max	Unit
7	P	Conversion time (Including sample time)	Short sample (ADLSMP = 0)	$t_{ADC}$	—	20	—	ADCK cycles
			Long sample (ADLSMP = 1)		—	40	—	
8	P	Sample time	Short sample (ADLSMP = 0)	$t_{ADS}$	—	3.5	—	ADCK cycles
			Long sample (ADLSMP = 1)		—	23.5	—	
9	P	Total unadjusted error	10-bit mode	$E_{TUE}$	—	$\pm 1$	$\pm 2.5$	LSB <sup>2</sup>
			8-bit mode		—	$\pm 0.5$	$\pm 1.0$	
10	P	Differential non-linearity	10-bit mode	DNL	—	$\pm 0.5$	$\pm 1.0$	LSB <sup>2</sup>
			8-bit mode		—	$\pm 0.3$	$\pm 0.5$	
			Monotonicity and no-missing-codes guaranteed					
11	C	Integral non-linearity	10-bit mode	INL	—	$\pm 0.5$	$\pm 1.0$	LSB <sup>2</sup>
			8-bit mode		—	$\pm 0.3$	$\pm 0.5$	
12	P	Zero-scale error	10-bit mode	$E_{ZS}$	—	$\pm 0.5$	$\pm 1.5$	LSB <sup>2</sup>
			8-bit mode		—	$\pm 0.5$	$\pm 0.5$	
13	P	Full-scale error $V_{ADIN} = V_{DDA}$	10-bit mode	$E_{FS}$	—	$\pm 0.5$	$\pm 1.5$	LSB <sup>2</sup>
			8-bit mode		—	$\pm 0.5$	$\pm 0.5$	
14	D	Quantization error	10-bit mode	$E_Q$	—	—	$\pm 0.5$	LSB <sup>2</sup>
			8-bit mode		—	—	$\pm 0.5$	
15	D	Input leakage error pad leakage <sup>3</sup> * $R_{AS}$	10 bit mode	$E_{IL}$	—	$\pm 0.2$	$\pm 2.5$	LSB <sup>2</sup>
			8 bit mode		—	$\pm 0.1$	$\pm 1$	

<sup>1</sup> Typical values assume  $V_{DDAD} = 5.0$  V, Temp = 25 °C,  $f_{ADCK} = 1.0$  MHz unless otherwise stated. Typical values are for reference only and are not tested in production.

<sup>2</sup> 1 LSB =  $(V_{REFH} - V_{REFL})/2^N$

<sup>3</sup> Based on input pad leakage current. Refer to pad electrical.

## 3.12 Flash Specifications

This section provides details about program/erase times and program-erase endurance for the flash memory. For detailed information about program/erase operations, see the reference manual.

**Table 14. Flash Characteristics**

Num	C	Characteristic	Symbol	Min	Typical <sup>1</sup>	Max	Unit
1	D	Supply voltage for program/erase	$V_{DD}$	2.7	—	5.5	V
2	D	Program/Erase voltage	$V_{PP}$	11.8	12	12.2	V

Table 14. Flash Characteristics (continued)

Num	C	Characteristic	Symbol	Min	Typical <sup>1</sup>	Max	Unit
3	C	V <sub>PP</sub> current Program Mass erase	I <sub>VPP_prog</sub> I <sub>VPP_erase</sub>	— —	— —	200 100	μA μA
4	D	Supply voltage for read operation 0 < f <sub>Bus</sub> < 10 MHz	V <sub>Read</sub>	1.8	—	5.5	V
5	P	Byte program time	t <sub>prog</sub>	20	—	40	μs
6	P	Mass erase time	t <sub>me</sub>	500	—	—	ms
7	C	Cumulative program HV time <sup>2</sup>	t <sub>hv</sub>	—	—	8	ms
8	C	Total cumulative HV time (total of t <sub>me</sub> & t <sub>hv</sub> applied to device)	t <sub>hv_total</sub>	—	—	2	hours
9	D	HVEN to program setup time	t <sub>pgs</sub>	10	—	—	μs
10	D	PGM/MASS to HVEN setup time	t <sub>nvs</sub>	5	—	—	μs
11	D	HVEN hold time for PGM	t <sub>nvh</sub>	5	—	—	μs
12	D	HVEN hold time for MASS	t <sub>nvh1</sub>	100	—	—	μs
13	D	V <sub>PP</sub> to PGM/MASS setup time	t <sub>vps</sub>	20	—	—	ns
14	D	HVEN to V <sub>PP</sub> hold time	t <sub>vph</sub>	20	—	—	ns
15	D	V <sub>PP</sub> rise time <sup>3</sup>	t <sub>vrs</sub>	200	—	—	ns
16	D	Recovery time	t <sub>rcv</sub>	1	—	—	μs
17	D	Program/erase endurance T <sub>L</sub> to T <sub>H</sub> = -40°C to 85°C	—	1000	—	—	cycles
18	C	Data retention	t <sub>D_ret</sub>	100	—	—	years

<sup>1</sup> Typicals are measured at 25 °C.

<sup>2</sup> t<sub>hv</sub> is the cumulative high voltage programming time to the same row before next erase. Same address can not be programmed more than twice before next erase.

<sup>3</sup> Fast V<sub>PP</sub> rise time may potentially trigger the ESD protection structure, which may result in over-current flowing into the pad and cause permanent damage to the pad. External filtering for the V<sub>PP</sub> power source is recommended. An example V<sub>PP</sub> filter is shown in Figure 19.

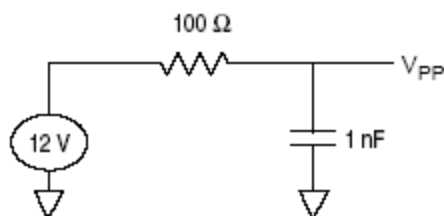
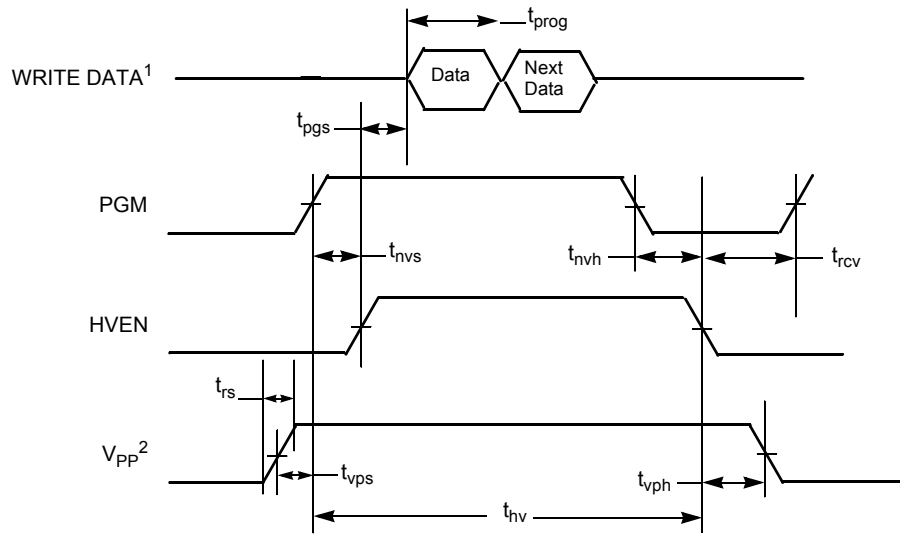
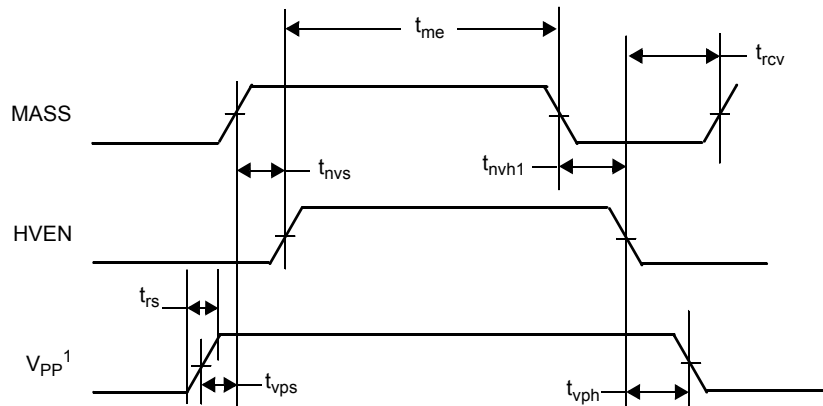


Figure 19. Example V<sub>PP</sub> Filtering



- <sup>1</sup> Next Data applies if programming multiple bytes in a single row, refer to *MC9RS08LE4 Reference Manual*.
- <sup>2</sup>  $V_{DD}$  must be at a valid operating voltage before voltage is applied or removed from the  $V_{PP}$  pin.

**Figure 20. Flash Program Timing**



- <sup>1</sup>  $V_{DD}$  must be at a valid operating voltage before voltage is applied or removed from the  $V_{PP}$  pin.

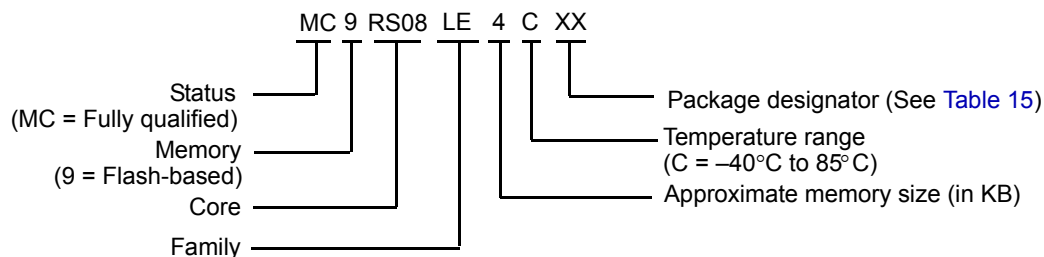
**Figure 21. Flash Mass Erase Timing**

## 4 Ordering Information

This section contains ordering numbers for MC9RS08LE4 devices. See below for an example of the device numbering system.

**Table 15. Device Numbering System**

Device Number	Memory		Package		
	Flash	RAM	Type	Designator	Document No.
<b>MC9RS08LE4</b>	4 KB	256 bytes	28 SOIC	WL	98ASB42345B

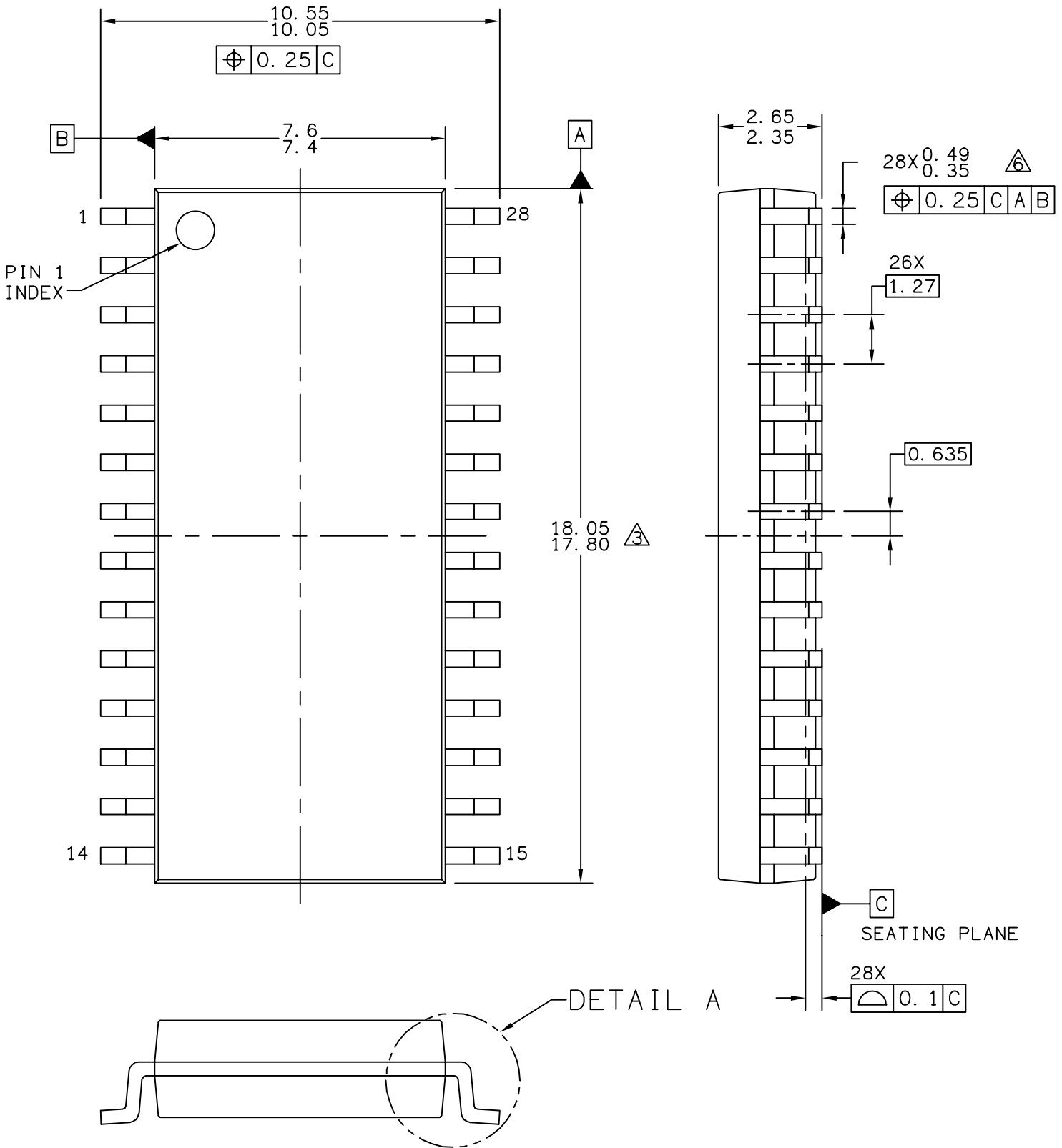


## 5 Mechanical Drawings

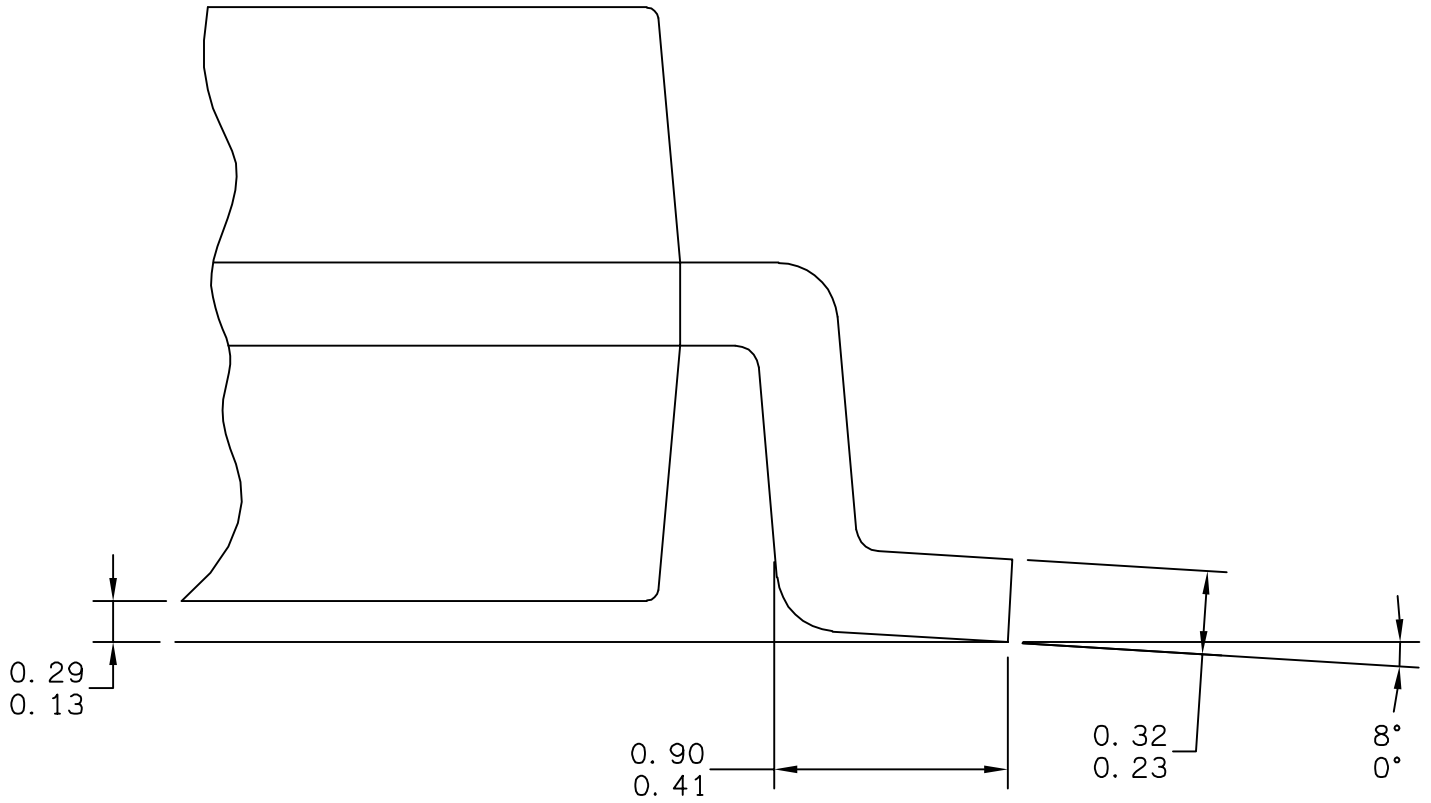
The following pages contain mechanical specifications for MC9RS08LE4 package options.

- 28-pin SOIC (small outline integrated circuit)





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	CASE NUMBER: 751F-05	10 MAR 2005	
	STANDARD: MS-013AE		



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	CASE NUMBER: 751F-05	10 MAR 2005	
	STANDARD: MS-013AE		



NOTES:

1. DIMENSIONS ARE IN MILLIMETERS.

2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

3. THIS DIMENSION DOES NOT INCLUDE MOLD PROTRUSION. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.

4. 751F-01 THRU -04 OBSOLETE. NEW STANDARD: 751F-05

5. THIS DIMENSION DOES NOT INCLUDE DAM BAR PROTRUSION ALLOWABLE DAM BAR PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF THIS DIMENSION AT MAXIMUM MATERIAL CONDITION.

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